

Search Notes

Application/Control No.

10/506,302

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

ISHIHARA ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	261	10/17/2006	HN
310	216	10/17/2006	HN
310	217	10/17/2006	HN
310	218	10/17/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR